



Reliability Data Report

Product Family R554

LTC2946 / LTC2956 / LTC2965 /
LTC2966 / LT4180

Reliability Data Report

Report Number: R554

Report generated on: Fri Apr 24 10:46:08 PDT 2015

OPERATING LIFE TEST					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HRS (+125°C) ¹	No. of FAILURES _{2,3}
QFN/DFN	314	1350	1418	394	0
SSOP/TSSOP	77	0905	0905	77	0
SOIC/MSOP	157	1413	1420	344	0
Totals	548	-	-	815	0

PRESSURE COOKER TEST AT 15 PSIG , +121 DEG C					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HRS	No. of FAILURES
SSOP/TSSOP	50	1007	1007	2	0
Totals	50	-	-	2	0

TEMP CYCLE FROM -65 TO 150 DEG C					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	No. of FAILURES
SSOP/TSSOP	50	1007	1007	5	0
Totals	50	-	-	5	0

THERMAL SHOCK FROM -65 TO 150 DEG C					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	No. of FAILURES
SSOP/TSSOP	50	1007	1007	5	0
Totals	50	-	-	5	0

(1) Assumes Activation Energy = 0.7 Electron Volts
 (2) Failure Rate Equivalent to +55 °C, 60% Confidence Level =14.54 FITS
 (3) Mean Time Between Failure in Years = 7851.81
 Note: 1 FIT = 1 Failure in One Billion Hours.
 Note 2: HAST, Temp Cycle & Thermal Shock are subjected to J-STD-020 MSL1 Preconditioning